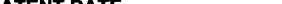




		Subclass
	Class	

PATENT NUMBER

U.S. **UTILITY Patent Application**

O.I.P.E.  SCANNED  Q.A. 	PATENT DATE 
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APPLICATION NO. 09/659211	CONT/PRIOR F	CLASS 438	SUBCLASS 650	ART UNIT 2812 2825	EXAMINER Everhart
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Noriyuki Hirayashiki

Alignment-mark detection methods and devices for charged-particle-beam microlithography, and microelectronic-device manufacturing methods comprising same

PTO-2040
12/89

Continued on Issue Slip Inside File Jacket

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____				ISSUE FEE	
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